

<b>Notice of References Cited</b>		Application/Control No. 09/517,579	Applicant(s)/Patent Under Reexamination HIRATSUKA ET AL.
		Examiner Ha T. Nguyen	Art Unit 2812

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	A	US-6152970	11-2000	Wei et al.	29	25.03
	B	US-				
	C	US-				
	D	US-				
	E	US-				
	F	US-				
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**FOREIGN PATENT DOCUMENTS**

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